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NATIONAL STANDARD OF THE

PEOPLE'S REPUBLIC OF CHINA

GB/T 47239.7-2026

Semiconductor devices-Flexible and stretchable semiconductor devices-Part 7: Test method for characterizing the barrier performance of thin film encapsulation for flexible organic semiconductor

半导体器件 柔性可拉伸半导体器件 第7部分：柔性有机半导体封装薄膜阻挡特性测试方法

(English Translation)

Issued on: October 30, 2026 **Implemented on: May 1, 2027**

Issued by: State Administration for Market Regulation;
Standardization Administration of China

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https://chinastandards.org/standards/gb-t-47239-7-2026

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1 Foreword

GB/T 47239.7-2026 was issued by State Administration for Market Regulation; Standardization Administration of China on 30 October 2026 and takes effect on 1 May 2027.

It is one of 9 parts of the GB/T 47239 series.

The GB/T prefix marks a recommended standard. It is not law in itself: it becomes binding when a contract names it, when a regulation or a mandatory standard refers to it, or when a producer declares conformity with it.

2 Scope Preview

GB/T 47239.7-2026 carries no ICS number and no Chinese Standard Classification code.

This catalogue holds 76,457 other GB/T standards.

Of the 47,415 GB/T standards that do carry an ICS number, 3,437 (7%) fall under ICS 77, in the field of metallurgy.

3 About this standard

Issued by: State Administration for Market Regulation; Standardization Administration of China

4 Related standards

Other parts of this standard:

GB/T 47239.1-2026 - Semiconductor devices - Flexible and stretchable semiconductor devices - Part 1: Bending test method for conductive thin films on flexible substrates

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GB/T 47239.2-2026 - Semiconductor devices - Flexible and stretchable semiconductor devices - Part 2: Evaluation method for electron mobility, sub-threshold swing, and threshold voltage of flexible devices

GB/T 47239.3-2026 - Semiconductor devices - Flexible and stretchable semiconductor devices - Part 3: Evaluation of thin film transistor characteristics on flexible substrates under bulging

GB/T 47239.4-2026 - Semiconductor devices - Flexible and stretchable semiconductor devices - Part 4: Fatigue evaluation for flexible conductive thin film on the substrate for flexible semiconductor devices

GB/T 47239.5-2026 - Semiconductor devices - Flexible and stretchable semiconductor devices - Part 5: Test method for thermal characteristics of flexible materials

GB/T 47239.6-2026 - Semiconductor devices - Flexible and stretchable semiconductor devices - Part 6: Test method for sheet resistance of flexible conducting films

GB/T 47239.8-2026 - Semiconductor devices - Flexible and stretchable semiconductor devices - Part 8: Test method for stretchability, flexibility and stability of flexible resistive memory

GB/T 47239.9-2026 - Semiconductor devices - Flexible and stretchable semiconductor devices - Part 9: Performance testing methods of one transistor and one resistor (1T1R) resistive memory cells

5 Classification and status

Prefix GB/T: recommended standard.

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